

Search Notes

Application/Control No.

09/473,830

Examiner

Shin-Lin Chen

Applicant(s)/Patent under
Reexamination

LEIDEN ET AL.

Art Unit

1632

SEARCHED

Class	Subclass	Date	Examiner
514	44		
424	93.21		
435	320.1		
435	455		
536	23.1		
536	23.5		
536	24.1	2/23/2006	<i>SLC</i>

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
514	44		
424	93.21		
435	320.1		
435/455; 536/23.1, 23.5, 24.1, AU interference search		2/23/2006	<i>SLC</i>

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated.	2/23/2006	<i>SLC</i>